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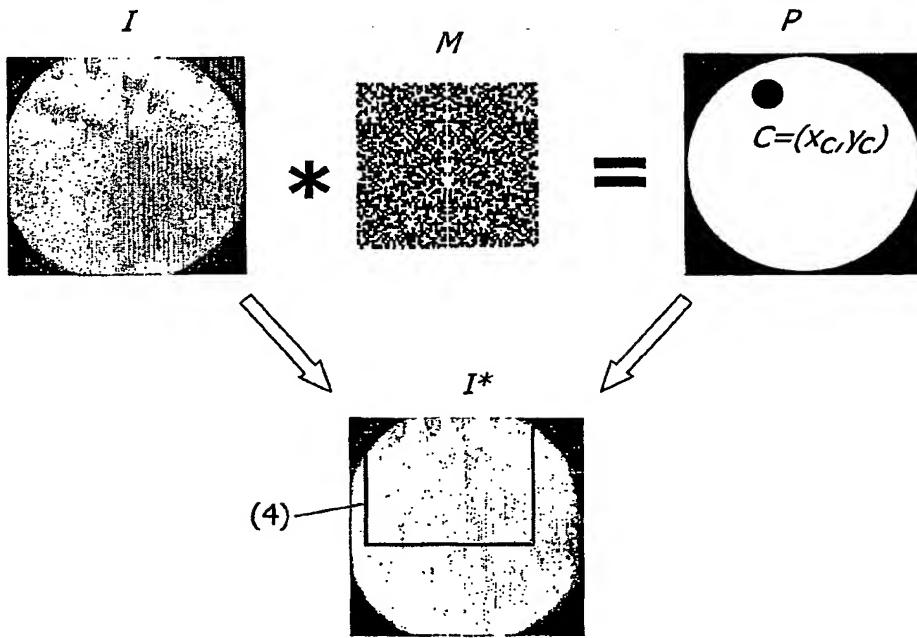
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(54) Title: METHOD OF DETERMINING THE POSITION OF AN OBJECT IN AN IMAGE



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(57) Abstract: The invention relates to a method of determining the position of an object in an (X-ray) image (I). A pattern of marking elements is attached to the object, wherein the marking elements are not visibly evident individually in the image (I), i.e. they form an invisible "watermark". By means of a correlation between the image (I) and a filter image (M) of the pattern of marking elements, however, the position of the marking elements, and thereby that of the object, can be localized in the image (I).

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